

DEFECT SAMPLE SYNTHESIS METHOD, TRAINING METHOD OF
DEFECT INSPECTION NETWORK, COMPUTER-READABLE
MEDIUM, COMPUTING SYSTEM, AND IMAGE INSPECTION
APPARATUS

ABSTRACT OF THE DISCLOSURE

A defect sample synthesis method includes steps of providing a normal sample and a synthesizer, inputting the normal sample to the synthesizer, allowing the synthesizer to generate a synthesized defect sample, inputting the synthesized defect sample to the synthesizer, and allowing the synthesizer to generate a restored normal sample.

FIG. 1